

Search Notes



Application/Control No.

10/757,782

Examiner

José V. Chen

Applicant(s)/Patent under
Reexamination

WUNSH ET AL.

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
108	28 26 27 12 14 13 40 161	9/14/15	JLC
206	769 770 326		
JAN 2017 5/18/16 JLC			
JAN 2017 9/12/16 JLC			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Long Base Gr. Fin 1007-ACT	9/12/15	JLC
JAN 2017	9/19/16	JLC